TOSHIBA Field Effect Transistor Silicon N Channel MOS Type $(\pi\text{-MOSIII}^{.5})$

2SK1486

Chopper Regulator, DC-DC Converter and Motor Drive Applications

 $\begin{array}{ll} \bullet & Low\ drain-source\ ON\ resistance & \vdots\ R_{DS}\ (ON) = 0.08\ \Omega\ (typ.) \\ \bullet & High\ forward\ transfer\ admittance & \vdots\ |Y_{fs}| = 14\ S\ (typ.) \\ \bullet & Low\ leakage\ current & \vdots\ I_{DSS} = 300\ \mu A\ (max)\ (V_{DS} = 300\ V) \\ \bullet & Enhancement-mode & \vdots\ V_{th} = 2.0{\sim}4.0\ V\ (V_{DS} = 10\ V,\ I_{D} = 1\ mA) \end{array}$

Maximum Ratings (Ta = 25°C)

Characteristics		Symbol	Rating	Unit	
Drain-source voltage		V_{DSS}	300	V	
Drain-gate voltage (R _{GS} = 20 kΩ)		V_{DGR}	300	V	
Gate-source voltage		V_{GSS}	±30	V	
Drain current	DC (Note 1)	I _D	32	Α	
	Pulse (Note 1)	I _{DP}	128		
Drain power dissipation (Tc = 25°C)		P_{D}	200	W	
Channel temperature		T _{ch}	150	°C	
Storage temperature range		T _{stg}	-55~150	°C	

Thermal Characteristics

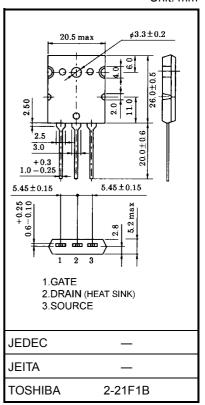
Characteristics	Symbol	Max	Unit
Thermal resistance, channel to case	R _{th (ch-c)}	0.625	°C/W
Thermal resistance, channel to ambient	R _{th (ch-a)}	35.7	°C/W

Note 1: Please use devices on condition that the channel temperature is below 150°C.

This transistor is an electrostatic sensitive device.

Please handle with caution.

Unit: mm



Weight: 9.75 g (typ.)

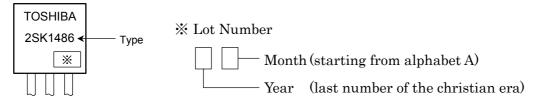
Electrical Characteristics (Ta = 25°C)

Charac	teristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage cu	rrent	I _{GSS}	V _{GS} = ±30 V, V _{DS} = 0 V	_	_	±100	nA
Drain cut-off cur	rent	I _{DSS}	V _{DS} = 300 V, V _{GS} = 0 V	_	_	300	μΑ
Drain-source br	eakdown voltage	V (BR) DSS	I _D = 10 mA, V _{GS} = 0 V	300	_	_	V
Gate threshold v	roltage	V _{th}	V _{DS} = 10 V, I _D = 1 mA	2.0	_	4.0	V
Drain-source Ol	N resistance	R _{DS (ON)}	I _D = 16 A, V _{GS} = 10 V	_	0.08	0.095	Ω
Forward transfer	admittance	Y _{fs}	V _{DS} = 10 V, I _D = 16 A	10	14	_	S
Input capacitano	е	C _{iss}			3500	_	
Reverse transfer	capacitance	C _{rss}	V _{DS} = 10 V, V _{GS} = 0 V, f = 1 MHz		800	_	pF
Output capacitar	nce	Coss	,		1250	_	
Switching time Fall	Rise time	t _r	V_{GS} V_{OV} V_{OUT} V_{DD} V_{DD} V_{DD}	_	255	_	- ns
	Turn-on time	t _{on}		_	325	_	
	Fall time	t _f		_	280	_	
	Turn-off time	t _{off}	Duty $\leq 1\%$, $t_{\rm W} = 10 \mu \rm s$	_	540	_	
Total gate charge (Gate-source plus gate-drain)		Qg			140	_	_
Gate-source charge		Q _{gs}	$V_{DD} \approx 240 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 32 \text{ A}$		60	_	nC -
Gate-drain ("miller") charge		Q _{gd}			80	_	

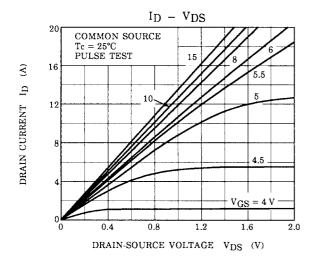
Source-Drain Ratings and Characteristics (Ta = 25°C)

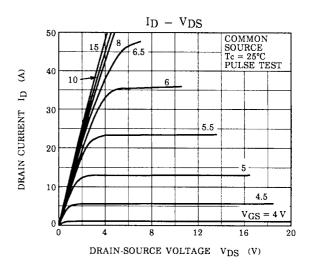
Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Continuous drain reverse current (Note 1)	I _{DR}		_	_	32	Α
Pulse drain reverse current (Note 1)	I _{DRP}		_		128	Α
Forward voltage (diode)	V_{DSF}	I _{DR} = 32 A, V _{GS} = 0 V	_	_	-1.8	V
Reverse recovery time	t _{rr}	I _{DR} = 32 A, V _{GS} = 0 V	1	615	1	ns
Reverse recovered charge	Q_{rr}	dI _{DR} / dt = 100 A / μs		6.8		μC

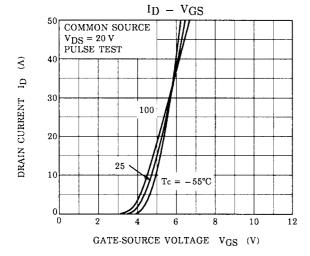
Marking

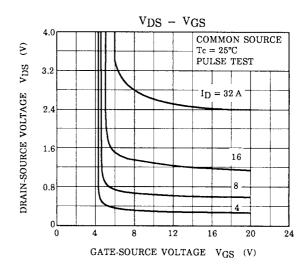


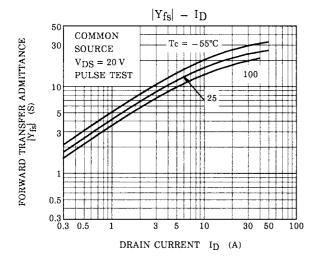
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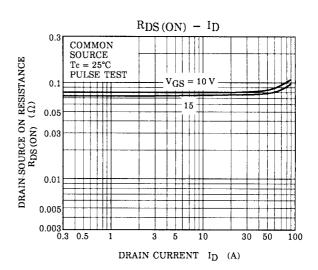




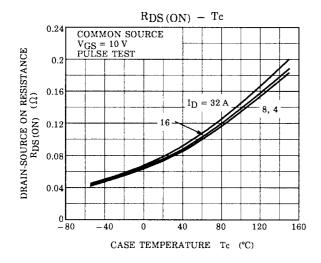


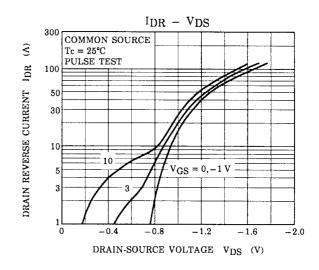


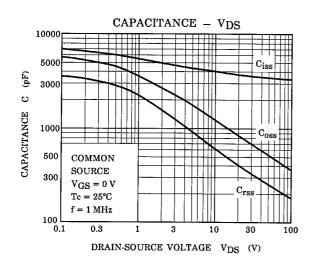


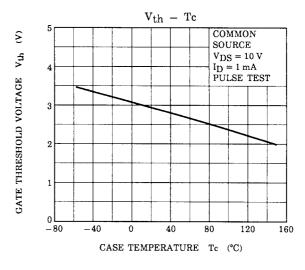


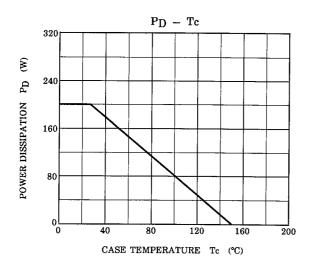
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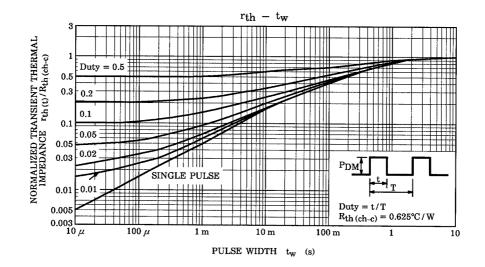




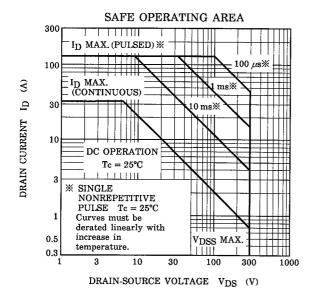




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